2PG002

N-channel enhancement mode IGBT

For plasma display panel drive For high speed switching circuits

■ Features

- \bullet Low collector-emitter saturation voltage: $V_{CE(sat)}$ < 2.4 V
- High speed hall time: $t_f = 190 \text{ nsec(typ.)}$

■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-emitter voltage (E-B short)	V _{CES}	410	V	
Gate-emitter voltage (E-B short)	V _{GES}	±30	V	
Collector current	I _C	40	A	
Peak collector current *	I _{CP}	160	A	
Pour distinction	P _C	40	W	
Power dissipation $T_a = 25^{\circ}C$		2.0	W	
Junction temperature	T_{j}	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

Note) *: PW \leq 10 us, Duty \leq 1.0%

■ Package

• Code

TO-220F-A1

- Marking Symbol: 2PG002
- Pin Name
 - 1. Gate
 - 2. Collector
 - 3. Emitter

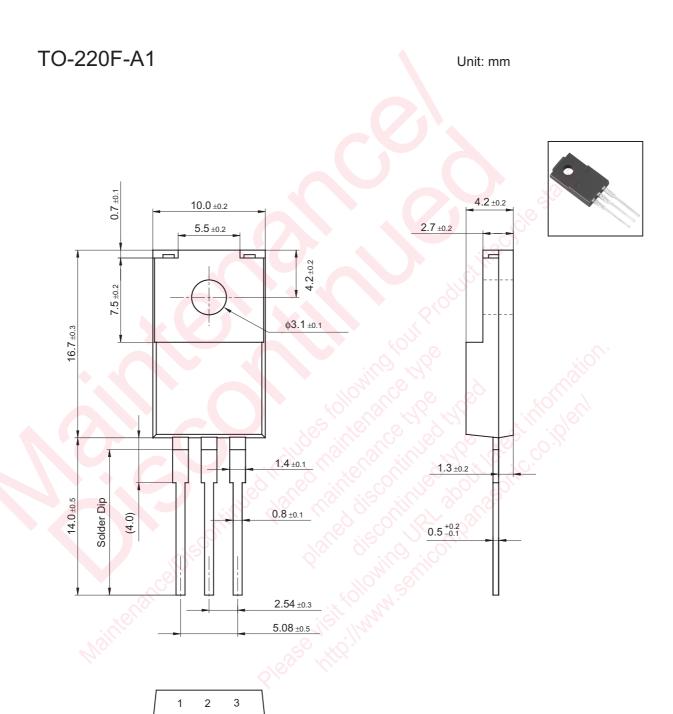
■ Internal Connection



■ Electrical Characteristics $T_C = 25$ °C±3°C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (E-B short)	V _{CES}	$I_C = 1 \text{ mA}, V_{GE} = 0$	410	1/10		V
Collector-emitter cutoff current (E-B short)	I _{CES}	$V_{CE} = 328 \text{ V}, V_{GE} = 0$) ()		50	μΑ
Gate-emitter cutoff current (E-B short)	I_{GES}	$V_{GE} = \pm 30 \text{ V}, V_{CE} = 0$			±1.0	μΑ
Gate-emitter threshold voltage	$V_{GE(th)}$	$V_{CE} = 10 \text{ V}, I_{C} = 1.0 \text{ mA}$	3.0		5.5	V
Collector-emitter saturation voltage	V _{CE(sat)}	$V_{GE} = 15 \text{ V}, I_{C} = 40 \text{ A}$		1.9	2.4	V
Short-circuit input capacitance (Common emitter)	Cies	100 CE1		1200		pF
Short-circuit output capacitance (Common emitter)	Coes	$V_{CE} = 25 \text{ V}, V_{GE} = 0, f = 1 \text{ MHz}$		150		pF
Reverse transfer capacitance (Common emitter)	C _{res}	jisi Ilah		25		pF
Gate charge load	Qg	Se **(5,1)		51		nC
Gate-emitter charge	Q _{ge}	$V_{CC} = 200 \text{ V}, I_{C} = 40 \text{ A}, V_{GE} = 15 \text{ V}$		7		nC
Gate-collector charge	Q_{gc}	X *		22		nC
Turn-on delay time	t _{d(on)}			96		ns
Rise time	t _r	$V_{CC} = 200 \text{ V}, I_C = 40 \text{ A},$		390		ns
Turn-off delay time	t _{d(off)}	$RL \approx 5 \Omega, V_{GE} = 15 V$		200		ns
Fall time	$t_{\rm f}$			190		ns

 $Note)\ \ Measuring\ methods\ are\ based\ on\ JAPANESE\ INDUSTRIAL\ STANDARD\ JIS\ C\ 7030\ measuring\ methods\ for\ transistors.$



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